#### IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Kwang Su Choe, et al. Examiner: Unknown

Serial No.: 10/674,647 Art Unit: 1762

Filed: September 30, 2003 Docket: YOR920030293US1 (16818)

Dated: October 11, 2007

For: THIN BURIED OXIDES BY LOW-DOSE

OXYGEN IMPLANTATION INTO MODIFIED

SILICON

Confirmation No: 4796

Mailstop Amendment Commissioner for Patents P. O. Box 1450 Alexandria, VA 22313-1450

### DECLARATION PURSUANT TO 37 C.F.R. 1.131

Sir:

We, Kwang Su Choe, Keith E. Fogel, Siegfried L. Maurer, Ryan M. Mitchell and Devendra K. Sadana hereby declare that:

- We are co-inventors of the subject matter described and claimed in the above-identified patent application.
- Prior to December 20, 2002, which is the effective filing date of U.S. Patent No.
   6,800,518 to Bendernagle et al., we have conceived and reduced to practice a semiconductor structure including a buried oxide layer in accordance with claims 1, 23 and 24 of the above-identified patent application.
- As evidence of conception and reduction to practice referred to in paragraph 2 above, we
  have annexed hereto Exhibit A and Exhibit B. Exhibit A is a true copy of IBM invention

disclosure YOR820010417, which was created prior to December 20, 2002. Exhibit B is a true copy of IBM invention disclosure YOR820010812, which was also created prior to December 20, 2002. Each of Exhibit A and Exhibit B teaches the basic features of the invention as claimed in claim 1, claim 23 and claim 24, including in particular the claimed oxygen implant dose of less than 10E17 oxygen ions per square centimeter.

Electron Micrographs attached are part of Exhibit B, all names and dates have been redacted in the preparation of this declaration.

4. We do hereby declare that all statements made herein of our own knowledge are true, and that all statements made on information and belief are believed to be true; and further that these statements were made with the knowledge that willful false statements and the like so made are punishable by fine or imprisonment or both under 18 U.S.C. § 1001, and that such willful statements may jeopardize the validity or enforceability of the patent.

Tanu	ary 24	8006	Thang Su	Choc	
Dated	-	<u>у</u>	Kwang Chin		
			.,		
Dated	2000		Keith E. Fogel		
Dated			Siegfried L. Maurer	-1.4	
Dated	-		Ryan M. Mitchell	No.	-
Dated	iii	· ·	Devendra K. Sadana	1 41	

disclosure YOR\$20010417, which was created prior to December 20, 2002. Exhibit B is a true copy of IBM invention disclosure YOR\$20010812, which was also created prior to December 20, 2002. Each of Exhibit A and Exhibit B teaches the basic features of the invention as claimed in claim 1, claim 23 and claim 24, including in particular the claimed oxygen implant dose of less than 10E17 oxygen ions per square centimeter. Electron Micrographs attached are part of Exhibit B, all names and dates have been redacted in the preparation of this declaration.

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Kwang Choe
Lough & Foll
Keith/E/Fogel
Siegfried L. Maurer
Plefitted T. Mamer
Ryan M. Mitchell
Devendra K. Sadana

2

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1 - SF	• 17
Dated	Kwang Choe
Dated	Keith E. Fogel
Dated	Siegfried L. Maurer
/0 /15 /2007 Dated	Am M. Mitchell
Dated	Devendra K. Sadana



# Disclosure YOR8-2001-0417

Prepared for and/or by an IBM Attorney - IBM Confidential

Required fields are marked with the asterisk ( $^{\star}$ ) and must be filled in to complete the form .

\*Title of disclosure (in English) A near zero oxygen dose SIMOX

#### Summary

Status	Fin	al Decision	(File)				
Final Deadline			1				
Final Deadline							
Reason							
Merged							
Disclosures	YO	R8-2001-08	12				
Docket Family	YO	R9-2003-02	93				
*Processing							
Location	Yor	ktown					
*Functional Area	select   (700	0) 700 Isaac	System	s Techno	logy & Science		
Attorney/Patent			-,0.0.	D, TOURIU	ogy & Science		
Professional							
IDT Team	select						
Submitted Date							
*Owning Division	select   RES	3					
Incentive	a processor and						
Program							
Lab							
.Technology							
Code							
PVT Score	71						
nventors with a Bli nventors:	ie Pages ei	ntry					
nventor Name		Inve Seri		Div/Dept	Inventor Phone	Manager Name	
denotes primary cont	act						
p.maily com	uut						

inventors without a Blue Pages entry

IDT Selection

Attorney/Palent Professional ID1 Toam

## Response Due to IP&L

#### \*Main Idea

- Describe your invention, stating the problem solved (if appropriate), and indicating the advantages of using the invention.
- To produce low cost SOI substrate by anodic etching epitaxial silicon growth and oxidation. First, select a silicon substrate and form a layer of prosus silicon on the upper surface. Then, treat the very top surface of the porous silicon with hydrogen to form a layer of single crystal silicon. Then form an epitaxial silicon layer of a desired thickness. Heat the structure in an oxidizing ambient to induce internal thermal oxidation of the porous region to create a buried oxide layer and at the same time a SOI structure,
- 2. How does the invention solve the problem or achieve an advantage, (a description of "the invention", No to hard-thing as appropriate)?

No ion implantation or bonding is necessary to form an SOI substrate. A wide range of the insulator thickness can be formed for example in the range from 100 A to 2 microns.

- 3. If the same advantage or problem has been identified by others (inside/outside IBM), how have those others solved it and does your solution differ and why is it better? Current practice is to use oxygen implantation or bonding to create SOI.
- 4. If the invention is implemented in a product or prototype, include technical details, purpose, disclosure details to others and the date of that implementation not reduced to practice at this time.

# \*Critical Questions (Questions 1-9 must be answered in English)

*Question 1	
On what date was the invention workable? 'lease format the dat (Workable means i.e. when you know that your-design will solve the problem)	e as MM/DD/YYYY
problem	
*Question 2	
Is there any planned or actual publication or disclosure of your invention to anyone outside IBM?	O Yes
	No     No
If yes, Enter the name of each publication or patent and the date published be Publication/Patent:	
	elow.
Date Published or Issued:	
Are you aware of any publications, products or patents that relate to this invention?	
	• Yes
If yes, Enter the name of each publication or patent and the date published be	O No
	low.
Date Published or Issued: 3 or 4 years ago.	
Question 3	
Has the subject matter of the invention	O Yes
Has the subject matter of the invention or a product incorporating the invention been sold, used internally in manufacturing, announced for sale, or included in proposal?	● No
proposal? Translacturing, amounced for sale, or included in	ı a
is a sale, use in manufacturing, product announcement, or proposal planned?	
product announcement, or proposal planned?	C Yes
If Yes identify the product if the	● No
If Yes, identify the product if known and indicate the date or planned date of sa proposal and to whom the sale, announcement or proposal has been or will be Product	le, announcements, or made.
/mulon/Rolease:	

Pp00 2

Code Name:

*Question 4	
Was the subject matter of your invention or a product incorporating your invention used in public and product incorporating your	O Yes
invention used in public, e.g., outside IBM or in the presence of non-IBMers?  If yes, give a date. Please format the date as MM/DD/YYYY	● No
7 1 Store State. I lease format the date as MM/DD/YYYY	
Question 5	0
Have you ever discussed your invention with others not employed at IBM?	○ Yes ● No
If yes, identify individuals and date discussed. Fill in the text area with the folloness of the individuals, the employer, date discussed, under CDA, and CDA.	owing Information, the A.#.
Question 6	
Was the invention, in any way, started or developed under a government	O Yes
	● No ·
f Yes, enter the contract number	O Not sure
Question 7 Vas the invention made in the course of any all	O Yes
Nas the invention made in the course of any alliance, joint development or ot- contract activities?	ier   No
f Yes, enter the following:	O Not Sure
Name of Alliance, Contractor or Joint Develope	er
Contract ID number	
Relationship contact name	
Relationship contact E-mail	
Relationship contact phone	
uestion 8	
ave you or any of the other investors	O Yes
	● No
Yes, please provide disclosure number below:	
41-0	
uestion 9	O Yes
e you, or any of the other inventors, aware of any related inventions sclosures submitted by anyone in IBM previously?	● No
Yes, please provide the docket or disclosure number or any other identifying i	
i any other identifying i	nformation below:
Justion 10	

###001-0417 A near zero oxygen dose SIMOX - continued	
	1
Manufacturers of enterprise servers	
Manufacturers of entry servers	
Manufacturers of workstations	
Manufacturers of PC's	
Non-computer manufacturers	
Developers of operating systems	
<ul> <li>Developers of networking software</li> </ul>	
Developers of application software	
Integrated solution providers	
Service providers	
Other (Please specify below)	
semiconductor wafer suppliers	
Question 11	
If the invention relates to a product or service that	in quitaide the control of
recommend IBM business unit(s), IBM location(s) provide a good evaluation of your invention:	is outside the scope of your business unit, please or individual(s) within IBM that you think would
	y the inventor and attorney to assist with the evalu
(The Patent Value tool can be used by the inventor(s invention.)	) to determine the potential licensing value of your
Market	
*Question 1: What is the anticipated annual market invention?	size (in dollars) that will be captured by your
and Gridonia	, , , , , , , , , , , , , , , , , , , ,
Greater than \$5B Reason(s) for above Answer:	
reason(s) for above Ariswer:	
Claims	
*Question 1: How new is the technical field?	
Future	
Reason(s) for above Answer:	
*Question 2: How central is the invention to the prod	ucl(s) which might be expected to protein the
	solo) which might be expected to contain the
Entire Product	
Reason(s) for above Answer:	
40 4	
*Question 3: What is the scope of the claim?	
Broad	
Reason(s) for above Answer:	
Portfolio Need	
*Question 1: What are the portfolio needs in the area	
Listed in PPM Needs	of your invention?
Reason(s) for above Answer: PPM 100 A4	
, ,	
Exploitation & Enforcement	
*Question 1: How easily can the use of the invention	hy a compelitor he detected?
WILLI WOLK	e) a semberror pe delected (
Reason(s) for above Answer:	
*Question 2: How easily can the use of the invention	oe avoided by a competitor?
	·

Page 4

With much work

Reason(s) for above Answer: the process is low cost

#### Business Value

\*Question 1: What percentage of the companies producing products in the field of this invention might Broadly cloned

Reason(s) for above Answer:

\*Question 2: What is the value of this patent to current or anticipated Alliance Activity between IBM and other companies? High value

Reason(s) for above Answer:

\*Question 3: What is the value of this patent to current or anticipated Technology Transfer Activity High value

Reason(s) for above Answer:

\*Question 4: Does it result in prestige to iBM?

Industry wide

Reason(s) for above Answer:

#### Final Decision

This decision was entered by Kathy (	Cognatello/Watson/IRM on/	
Decision. File		
PPM Area: 100 - Solid State Technologie of Final Decision:	ologies Attorney Rating: 2	

# Additional filing information

Planned Filing date:

Filing comments:

# Additional decision comments

#### Final Decison History

Entered on 5

Merged Disclosures: YOR8-2001-0812

# Post Disclosure Text & Drawings

To add additional information related to this disclosure once it has been submitted, click the action button below and a new document will be opened for you to enter the new information. To view existing post disclosure information, double-click on the item in the list below (if there has been additional information entered), and the document will open for you to view. Date entered Post disclosure information (comments and drawings)

Form Revised

, 10 to 1



Disclosure YOR8-2001-0812 Prepared for and/or by an IBM Attorney - IBM Confidential

Required fields are marked with the asterisk (  $^{\star}$  ) and must be filled in to complete the form .

\*Title of disclosure (in English)
Thin Buried Oxides by Oxygen Implantation into Modified Silicon

## Summary

Status	Final Decision (File/Merge)
Final Deadline	A MANUAL (I MANUAL (ID)
Final Deadline	
Reason	
Primary	
Disclosure	YOR8-2001-0417
Docket Family	YOR9-2003-0293
Processing Location	Yorktown
*Functional Area	select (700) 700 Isaac-Systems, Technology & Science
Altorney/Patent	(***) / 50 Istac-Systems, Technology & Science
Professional	
IDT Team	select
Submitted Date	
*Owning Division	select RES
Incentive	The second secon
Program	
Lab	
.Technology	
Code	
PVT Score	71

#### Inventors with a Blue Pages entry Investore

Inventor Name	Inventor Serial Div/Dept	Inventor Phone	Manager Name	
> denotes primary contact		-		

Inventors without a Blue Pages entry

IDT Selection

Attorney/Patent

Professional IDT Team Response Due to IP&L

#### \*Main Idea

Describe your invention, stating the problem solved (if appropriate), and indicating the advantages of

Thin continuous buried oxides (< 300A) are extremely difficult to fabricate by convetional methods, such as SIMOX or wafer bonding. There is no known demonstration of such tayers in prior art to our knowledge. High sufrace energy associated with the formation of such oxides lend to make them ball up during their fabrication resulting in a discontinous and fragmented oxide layer.

The present invention overcomes this difficulty by a novel method which includes the following steps: (i) treating the surface of a Si substrate by a process which creates high concentration of vacancies and voids in the surface region, (ii) growing a single crystal St layer above the treated surface, (iii) implanting oxygen into the novel structure, and (iv) annealing the implanted samples at high temperatures (>1100C). Continuus buried oxide layers of < 500A can be created controllably by this method.

We now describe details of each step. For step (i) anodic oxidation of Si is performed in a HF(49%) or HF/ethanol electrolyte such that a very low density porous Si, or highly vacancy rich Si layer is created The thickness and porosity of this layer can be controlled by a number of parameters, such as the toal current flow during anodic oxidation/etching, time, HF concetration, HF/ethanol ratio, Si substrate doping and doping concentration etc. For step (ii) conventional Si epitaxial reactors such as those made by ASM or Applied Material can be used. For step (iii) a conventional or SIMOX implanter can be used. Typical охуде implant dose should be < 1E17 cm-2. For step (iv) convetional furnaces or those used for SIMOX

Figures below show how the invention has been reduced into practice. The first micrograph in each case shows the region which was untreated. It is clear that the present invention has a profound effect on the





Z5X-063001A1-203.ti Z5X-063001A1-200.ti

Z5X-200 shows discontinous buried oxide. This region did not receive any porous-Si treatment. ZSX-2003 shows a thin and continous buried oxide. This region did receive the porous-Si treatment.



ICX-063001A1-203.t

ICX-203 shows a thin and continous buried oxide. This region did receive the porous-Si treatment. Oxygen dose in this case is 1E17 cm-2 at 210 keV Major Claims

- A method to form ultrathin buried oxide layers by implating oxygen into a Si substrate containing a buried vacancy-rich region, and annealing the said structure at temperatures of > 1100C.
- Controlling the oxide thickness by the implanted oxygen dose.

- 6-2001-0812 Thin Buried Oxide v Oxygen Implantation Into Modified Silicon continu
- Controlling the oxide thickness by internal thermal oxidation.
- How does the invention solve the problem or achieve an advantage.(a description of "the invention", including figures inline as appropriate)?

The invenion opens up new frontiers in SI technology for multiple applications, such as, buried ground plane MOSFETs, Double gate MOSFETs etc. The process is quite manufacturable and therefore can be applied to IBM's future product lines.

- 3. If the same advantage or problem has been identified by others (inside/outside IBM), how have those others solved it and does your solution differ and why is it better? The others have not yet been able to solve this problem.
- 4. If the invention is implemented in a product or prototype, include technical details, purpose, disclosure details to others and the date of that implementation. CMOS 11S and beyond technology generation

\*Critical Questions (Questions 1-9 must be answered in English)

*Question 1	
On what date was the invention workable? Please format the dat (Workable means i.e. when you know that your design will solve the problem	e as MM/DD/YYYY
that your design will solve the problem	)
*Question 2	
Is there any planned or actual publication or disclosure of your invention to anyone outside IBM?	O Yes ● No
If yes, Enter the name of each publication or patent and the date published be Publication/Patent: Date Published or issued:	elow.
Are you aware of any publications, products or patents that relate to this invention?	O Yes
If yes, Enter the name of each publication or patent and the date published be Publication/Patent: Date Published or Issued:	No No
Question 3	
Has the subject matter of the invention or and the	O Yes
Has the subject matter of the invention or a product incorporating the invention peen sold, used internally in manufacturing, announced for sale, or included in proposal?	n ● No na
s a sale, use in manufacturing, product announcement, or proposal planned?	O Yes
	_
f Yes, identify the product if known and indicate the date or planned date of sa proposal and to whom the sale, appointed to proposal her high the	● No
Product Product Profusion/Release: Code Name: Date: To Whom:	made.
f more than one, use cut and paste and append as necessary in the field provi	ided.
Question 4	Oyes
Vas the subject matter of your invention or a product incorporating your wention used in public, e.g., outside IBM or in the presence of non-IBMers?	● No
yes, give a date. Please format the date as MM/DD/YYYY	

			'n
1		•	

*Question 5	O Yes
Have you ever discussed your invention with others not employed at iBM?	
If yes, identify individuals and date discussed. Fill in the text area with the followers of the individuals, the employer, date discussed, under CDA, and CD	llowing information, the A #.
*Question 6	
Was the invention, in any way, started or developed under a government	O Yes
and the projecti	● No
If Yes, enter the contract number	O Not sure
Question 7	
Was the invention made in the course of any alliance, joint development or of contract activities?	O Yes
If Yes, enter the following:	O Not Sure
Name of Alliance, Contractor or Joint Develop	er
Contract ID number	
Relationship contact name	
Relationship contact E-mail	
Relationship contact phone	
Question 8	
Have you, or any of the other inventors, authority and	O Yes
	● No
f Yes, please provide disclosure number below:	
Question 9	
VE YOU, OF any of the other inventors	O Yes
Are you, or any of the other inventors, aware of any related inventions isclosures submitted by anyone in IBM previously?	No No
Yes, please provide the docket or disclosure number or any other identifying	
	information below:

What type of companies do you expect to compete with inventions of this type? Check all that apply.

	8-2001-0812 Thin Buried Oxides * Oxygen Implantation Into Modified Silicon - continue
7	
	Manufacturers of enterprise servers
	Manufacturers of entry servers
	Manufacturers of workstations
	Manufacturers of PC's
	Non-computer manufacturers
	Developers of operating systems
	Developers of networking software
	Developers of application software
	Integraled solution providers
	Service providers
	Other (Please specify below)
	Question 11
	If the invention relates to a product or service that is outside the scope of your business unit, please recommend IBM business unit(s), IBM location(s) or individual(s) within IBM that you think would provide a control or the control of the cont
	provide a good evaluation of your invention:
	n/a
*!	atent Value Tool (Optional - this may be used by the inventor and attorney to assist with the evalu
(	The Patent Value tool can be used by the inventor(s) to determine it
ì	The Patent Value tool can be used by the inventor(s) to determine the potential licensing value of your ovention.)
	Tarket
	Question 1: What is the anticipated annual market size (in dollars) that will be captured by your
i	evention?
	Greater than \$5B
F	leason(s) for above Answer:
,	laims
	Question 1: How new is the technical field?
F	ulure
	leason(s) for above Answer;
*	Question 2: How central is the invention to the product(s) which might be expected to contain the
**	venilon;
	lain ein ein ein ein ein ein ein ein ein e
F	eason(s) for above Answer:
	Dungtion 2s Miles to the control of
E	Question 3: What is the scope of the claim?
	eason(s) for above Answer:
•	oddon(s) for above Allswei.
P	ortfolio Need
*(	Question 1: What are the portfolio needs in the area of your invention?
L	sted in PPM Needs
	eason(s) for above Answer:
E	xploitation & Enforcement
*(	Question 1: How easily can the use of the invention by a competitor be detected?
	III WOLK
R	pason(s) for above Answer:
*(	Question 2: How easily can the use of the invention be avoided by a competition?

Риро 5

much work

Reason(s) for above Answer:

Rusiness Value

\*Question 1: What percentage of the companies producing products in the field of this invention might use this invention?

Broadly cloned

Reason(s) for above Answer:

\*Question 2: What is the value of this patent to current or anticipated Alliance Activity between IBM and other companies?

High value Reason(s) for above Answer:

\*Question 3: What is the value of this patent to current or anticipated Technology Transfer Activity between IBM and other companies?

High value

Reason(s) for above Answer:

\*Question 4: Does it result in prestige to IBM?

Industry wide

Reason(s) for above Answer:

#### Final Decision

This decision was entered by

Decision: File/Merge Status: N/A Merged with disclosure number: YOR8-2001-0417

Date of Final Decision:

Additional filing information

Planned Filing date:

Filing comments:

#### Additional decision comments

#### Final Decison History

Entered on File/Merged with: YOR8-2001-0417 Docket(s) Family: YOR920030293

#### Post Disclosure Text & Drawings

To add additional information related to this disclosure once it has been submitted, click the action button below and a new document will be opened for you to enter the new information. To view existing post disclosure information, double-click on the item in the list below (if there has been additional information entered), and the document will open for you to view.

Date entered Post disclosure information (comments and drawings)